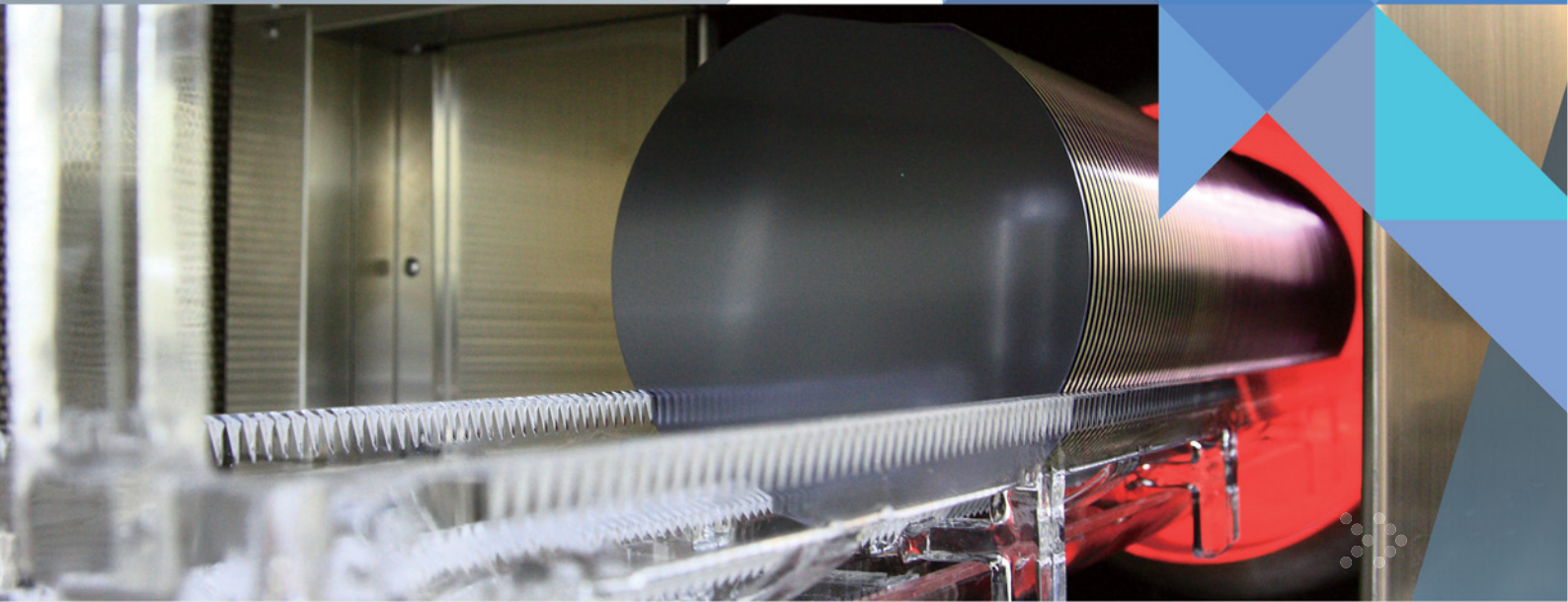




Capability

# Dedicated MEMS



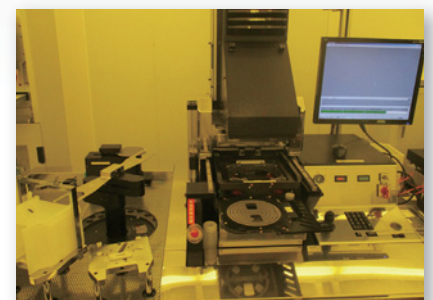
## **MEMS Thin Film Deposition / Ion Implanter / Thermal Treatment :**

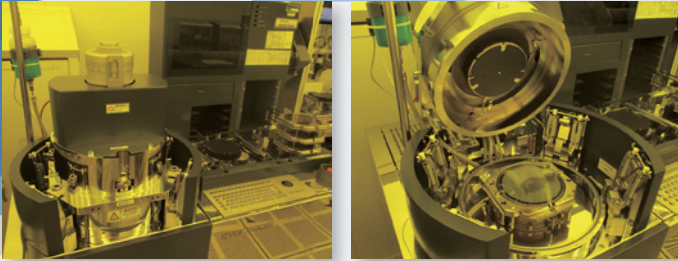
- Sputtering: Al, AlCu, AlSiCu, Cu, Pt, Ta, Ta<sub>2</sub>O<sub>5</sub>, Ti, TiN, Au, TaAl, Cr, NiCr, TiW
- E-Gun: Ti, Au, Cu, Pt, Ni, Ag, Cr, Al
- PECVD: α-Si, SiN, SiO<sub>2</sub>, SiC, PSG, BPSG
- LPCVD: SiN, Poly-Si
- High Current Implanter: up to 160 keV
- Medium Current Implanter: up to 250 keV
- Thermal Oxidation, Annealing, Alloy, and RTP
- Others: Cu electroplating



## **Photolithography :**

- 5X G-line Stepper: 1 μm Resolution, Registration < 0.2 μm
- 1X Double Side Aligner: 3 μm Resolution, 2.0 μm overlay control for single side alignment & 4.0 μm overlay control for double side alignment
- Coater Track
- Double Side Coater / Developer System
- Spray Coater
- Developer Track
- Polyimide, BCB, SU8





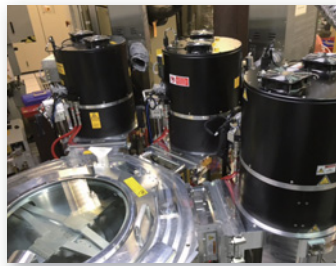
#### Wafer Bonding :

- Anodic Bond for Silicon or SOI on Glass Wafers
- Sandwich Bonding: Glass-Si-Glass, Si-Glass-Si
- Fusion Bond with or without Cavities
- BCB Adhesive Bond
- Au/Si, Au/Sn, Ge/Al Eutectic Bond
- Bond Alignment Accuracy  $\pm 5\mu\text{m}$

#### Etching :

##### DRY Etch:

- Metal Etcher
- Poly Si Etcher
- ICP Deep Si Etcher
- Oxide / SiN Etcher



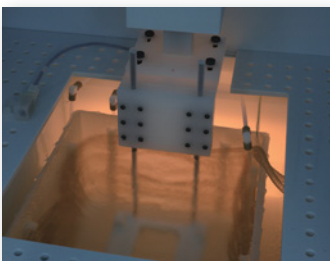
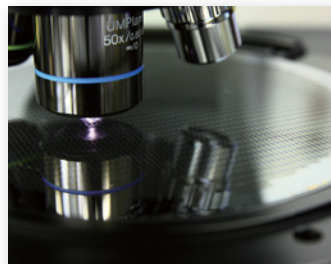
##### WET Etch:

- Wafer Cleaning Bench
- PR Stripper
- Metal Etcher
- Oxide Etcher
- SiN Etcher
- Metal Lift-off
- KOH Etcher with ECE Stop
- Scrubber for Particle Removal



#### Metrology & Testing :

- SEM, White-light Interferometer, IR Microscope
- Energy Dispersive X-ray Spectroscopy
- Wafer Probing and Dicing



#### NMOS Process Capability :

- Voltage: 5v / 12v / 18v
- Gate Length: 1 $\mu\text{m}$
- Isolation Structure: LOCOS
- BPSG as ILD Layer and Al Contact Holes

